

PATENT

Case Docket No.:	2001	P 11914	US

Date: September 28, 2001



ASSISTANT COMMISSIONER FOR PATENTS Washington, D.C. 20231
Box PATENT APPLICATION

Sir:

Transmitted herewith for filing is the patent application of:

Inventor(s):

Linda Chen and Larry Varnerin

For: DIRECT, NON-DESTRUCTIVE MEASUREMENT OF RECESS DEPTH IN A WAFER

This application includes:

Express Mail Label No.:

10	pages: specification and claims sheets of drawings, formal/ _X_ Informal photographs			
Also en	closed is:			
	An Assignment of the invention to Assignee(s):			
	X Infineon Technologies North America Corp.			
	International Business Machines Corporation or ITR, LP; IT AG; UMC, etc.			
	A certified copy of application			
X	Declaration and Power of Attorney			
X	Information Disclosure Statement pursuant to 37 CFR 1.56			
	X Form PTO-1449			
	Form PTO-1595			
Y	Poet Card			

The filing fee has been calculated as shown below:

FOR:	(Col. 1) NO. FILED	(Col. 2) NO. EXTRA RATE	OTHER THAN A SMALL ENTITY FEE	
BASIC FEE	XXXXXXX	xxxxxxxx	XXXXX	\$710
TOTAL CLAIMS	<u>10</u> - 20 =	<u>0</u>	X \$18 =	\$ <u>0</u>
INDEP CLAIMS	<u>2</u> -3=	<u>0</u>	X \$80 =	\$ <u>0</u>
* MULTIPL	+ 270 =	\$0		
ASSIGNMENT(S) <u>0</u>			X \$40 =	\$0

TOTAL \$710.00

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A fee of \$0.00 to cover recordation of the Assignment(s). <u>19-2179</u> in the amount of <u>\$710.00.</u> Please charge my Deposit Account No. Х duplicate copy of this sheet is enclosed. The Commissioner is hereby authorized to charge payment of the following fees associated with this communication or credit any overpayment to Deposit Account No. 19-2179. A duplicate copy of this sheet is enclosed. Any additional filing fees required under 37 CFR 1.16. Any patent application processing fees under 37 CFR 1.17. The Commissioner is hereby authorized to charge payment of the following fees during the <u>x_</u> pendency of this application or credit any overpayment to Deposit Account No. 19-2179. A duplicate copy of this sheet is enclosed. Any patent application processing fees under 37 CFR 1.17 Any filing fees under 37 CFR 1.16 for presentation of extra claims

Date: 9/28/01

Respectfully submitted,

Stanton C. Braden Registration No. 32,556 Attorney for Applicant

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APPLICATION FOR LETTERS PATENT OF THE UNITED STATES

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TITLE OF INVENTION: DIRECT, NON-DESTRUCTIVE MEASUREMENT OF RECESS DEPTH IN A WAFER

> TO WHOM IT MAY CONCERN, THE FOLLOWING IS A SPECIFICATION OF THE AFORESAID INVENTION